

**Amendments to the Specification:**

Please replace the paragraph at page 12, lines 25-30 with the following amended paragraph:

The first flip flop 601 receives data DATA from a semiconductor device (not shown), is synchronized with a first clock signal CLK1, and outputs data DATA. A second flip flop 602 receives the output signal from the first flip flop 601, is synchronized with the first clock signal CLK1, and outputs the output signal of the first flip flop 601. In FIG. ~~[[7]]~~6, a plurality of flip flops 601, 602, 603, and 604 and the data output buffer 600 are connected to each other as shown ~~in FIG. 6.~~

Please replace the paragraph at page 13, lines 8-13 with the following amended paragraph:

Hereinafter, the operation of the data output buffer 600 will be described with reference ~~[[with]]~~to FIG. 6. After a semiconductor device is tested, data DATA to be output is input to the data output buffer 600. Here, since the semiconductor device operates at a speed that is higher than an operating speed of the test equipment (not shown), the data output buffer is provided to interface data output at a high speed with the operating speed of the test equipment.